

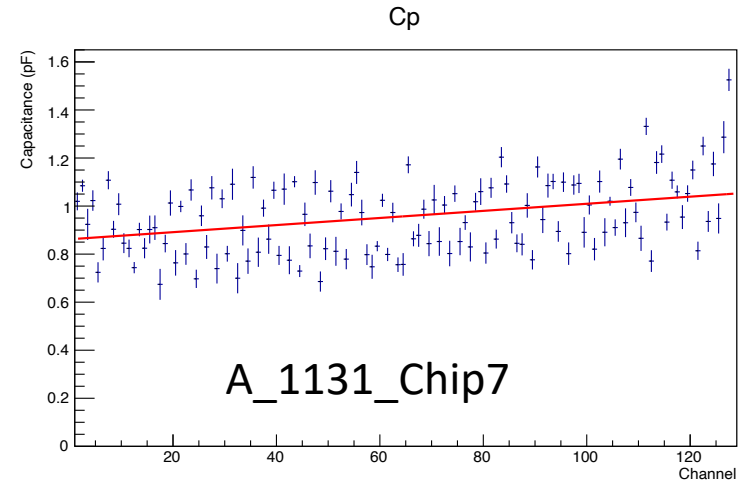
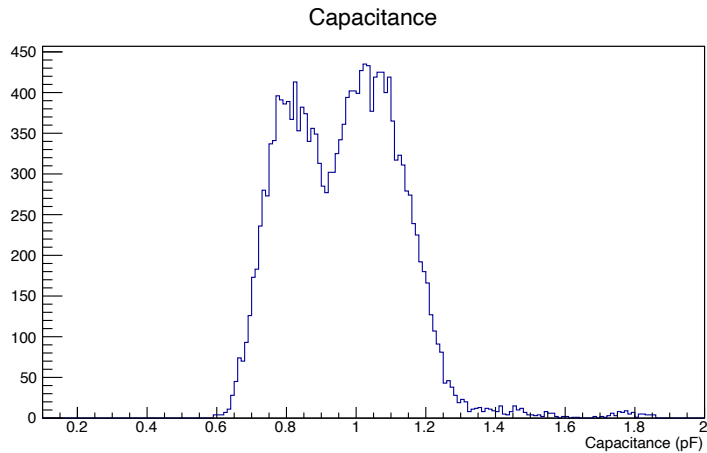
Silicon Sensor Ranking status

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Introduction

- We need to establish a figure of merits based on which we can rank silicon sensors
- That means we need a requirements to determine:
 - Whether the sensor is GOOD or not
 - Whether the sensor is BAD or not
 - Or neither of those (further investigation needed)
- For first look we have set of quantities from root tree provided by Kai-Yu:
 - 18 sensors
 - Each sensor has 26 chips, but only 8 chips **has measurement**

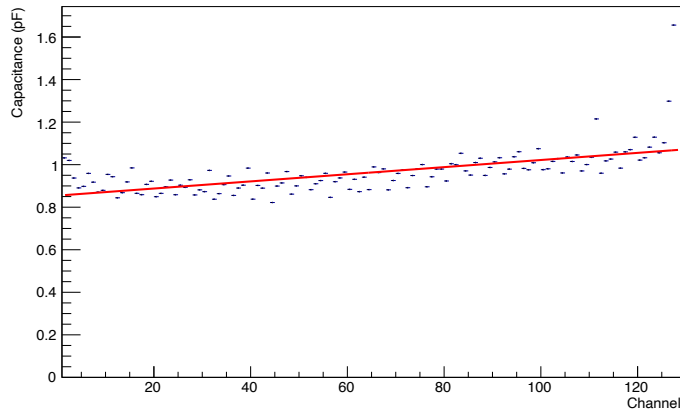
Capacitance RAW distribution



Correction needed

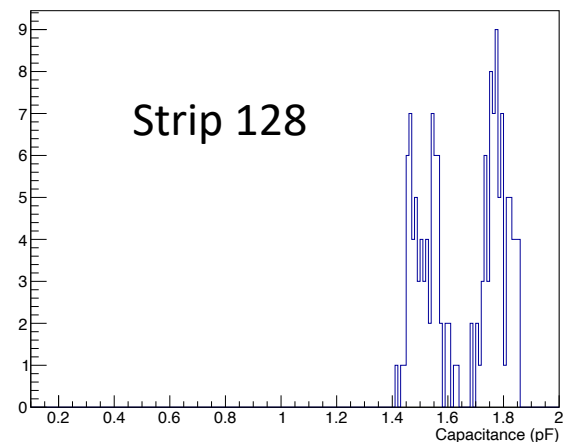
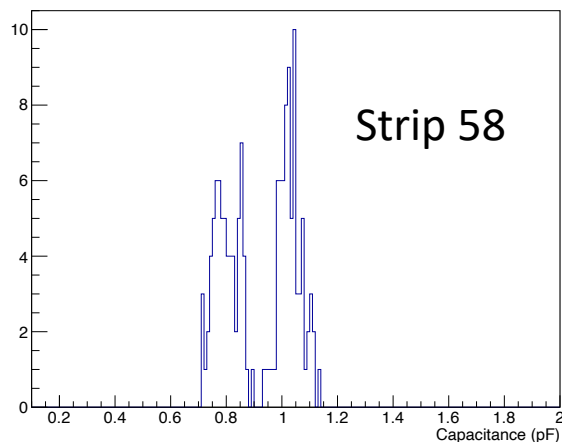
Capacitance RAW distribution

Average capacitance of each strip



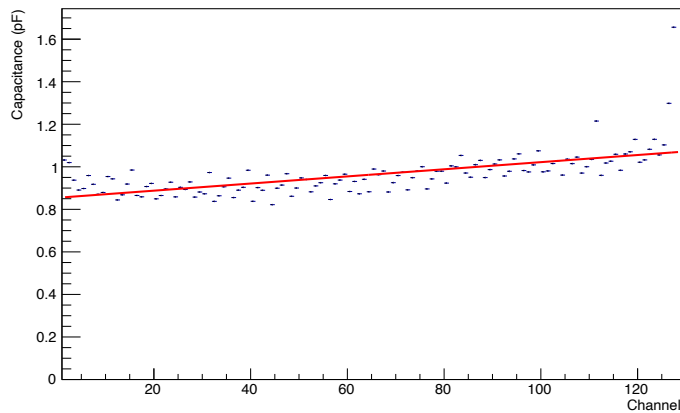
Plan: Shift each strip value so all all strip distributions have same mean

Strips 112, 127, 128 shifted manually

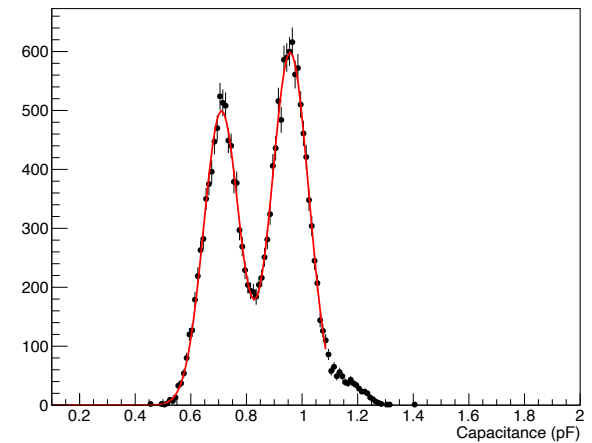


Capacitance distribution – linear shift

Average capacitance of each step



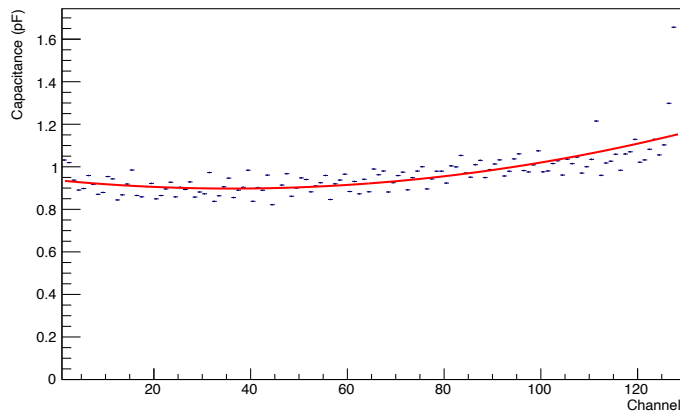
Double Gaussian fit



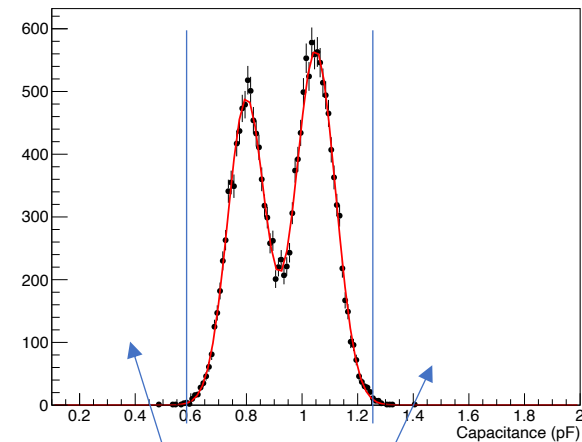
Non Gaussian tail

Capacitance distribution – quadratic shift

Average capacitance of each strip



Double Gaussian – good fit



BAD strip

If $((C_p - 1stMean < -3sigma) \ || \ (C_p - 2stMean > 3sigma))$ BAD strip

First ideas for ranking

- ❖ Double Gaussian fit of the shifted capacitance
- ❖ Shift based on 2nd order polynomial fit
- ❖ Lack of the method: what about the values between the two means?
- ❖ Average values of a strip do not converge – should we shift each strip manually?